

**Search Notes**

Application/Control No.

10/784,994

Examiner

Patrick M. Moore

Applicant(s)/Patent under  
Reexamination

FUJIBAYASHI, AKIRA

Art Unit

2188

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PLUS Search from EIC (50 Max)	11/10/2005	PMM
707/100,200,201; 709/215,217,219,226; 711/162,114,112,147; Narrowed with Text Search	11/10/2005	PMM
Text Search for Mirrored Pair RO and R/W modes	11/17/2005	PMM